

Notice of References Cited

Application/Control No.

10/041,829

Applicant(s)/Patent Under
Reexamination
NAKANISHI ET AL.

Examiner

David Y. Chung

Art Unit

2871

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,825,543	10-1998	Ouderkirk et al.	359/494
	B	US-6,517,914	02-2003	Hiraishi, Masanori	428/1.1
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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